

第 19 屆台灣靜電放電防護技術暨可靠度技術研討會  
2021 Taiwan ESD and Reliability Conference (TESDC-2021)  
議程表 Program

**2021 年 11 月 3 日(三) (Wednesday, Nov. 3, 2021) -- Tutorial Day**

08:50 ~ 09:00	Registration & Exhibition Open
09:00 ~ 10:30	<b>Tutorial A</b> <b>有效率的 ESD/EOS 防護設計技術</b> 蔡耀城 晶焱科技
	Chairman: 吳振忠
10:30 ~ 10:50	Coffee Break
10:50 ~ 12:20	<b>Tutorial B</b> <b>ANSI/ESD S20.20 標準介紹</b> 邱銘輝 SGS
	Chairman: 吳振忠
12:20 ~ 13:30	Lunch
13:30 ~ 15:00	<b>Tutorial C</b> <b>The Requirement of Functional Safety and Security for Automotive Product</b> Jeff Chang SGS
	Chairman: 林鴻志
15:00 ~ 15:20	Coffee Break
15:20 ~ 16:50	<b>Tutorial D</b> <b>Understanding and Prediction of Degradation in Engineering Systems</b> 陳始明 長庚大學
	Chairman: 林鴻志

**2021 年 11 月 4 日(四) (Thursday, Nov. 4, 2021) -- Conference Day 1**

09:20 ~ 09:40	<b>T-ESDA Member Registration</b>
09:40 ~ 10:00	<b>T-ESDA 第十一屆第一次會員大會、ESD 產學聯盟說明會</b>
10:00 ~ 10:10	<b>Coffee Break</b>
10:10 ~ 10:30	<b>TESDC-2021 Opening</b>
10:30 ~ 11:30	<b>Keynote Speech (I)</b> <b>Consideration of Parasitic Capacitance and Discharge Waveform in Multi-pin ESD Tester</b> <i>Masanori Sawada</i> <i>Hanwa</i>
	<b>Chairman: 柯明道</b>
11:30 ~ 12:30	<b>Invited Talk (I)</b> <b>ESD Robustness of Die-to-Die Interfaces – Set The Stage for Heterogenous Integration</b> <i>Harald Gossner</i> <i>Intel</i>
	<b>Chairman: 柯明道</b>
12:30 ~ 13:40	<b>Lunch</b> <b>(T-ESDA 理監事會、TESDC-2021 TPC Meeting)</b>
13:40 ~ 15:40	<b>Session A – ESD/EOS (I)</b>
	<b>RC-Diode ESD Protection Design for RF and Microwave Applications</b> <i>Ting-Hsin Yeh, Yi-Quan Fu, and Chun-Yu Lin</i>
	<b>低壓 CMOS 製程之電源箝制靜電放電防護電路</b> <i>林健群、傅義全、林群祐</i>
	<b>Study on ESD Characteristics of Low-Voltage Silicon-Carbide Devices</b> <i>Yu-Hsin Li, Yu-Xin Wen, Te-Kai Tsai, Chia-Lung Hung, Bing-Yue Tsui, and Ming-Dou Ker</i>
	<b>Optimized Local I/O ESD Protection in FinFET Technology for 2.5D and 3D hybrid integration</b> <i>Bart Keppens and Johan Van der Borgh</i>
<b>Chairman: 唐天浩</b>	
15:40 ~ 16:00	<b>Coffee Break</b>
16:00 ~ 17:00	<b>Invited Talk (II)</b> <b>ESD Reliability Challenges in Emerging STCO Scaling Era: Next to FinFET, How ESD will Suffer?</b> <i>Shih-Hung Chen</i> <i>imec</i>
	<b>Chairman: 陳東暘</b>

**2021 年 11 月 5 日(五) (Friday, Nov. 5, 2021) -- Conference Day 2**

09:10 ~ 09:30	<b>Registration &amp; Exhibition Open</b>
09:30 ~ 10:30	<b>Session B – Reliability</b>
	<b>應力誘發界面陷阱與氧化層陷阱電荷對 High-K/Metal Gate Ge-pMOSFETs 的退化影響</b> 林舉文、蔡岱廷、張嘉哲、許庭豪、黃至堯、張廖貴術、邱福千
	<b>硼摻雜氧化鋅薄膜電阻式記憶體特性研究</b> 陳亭佑、謝佳紘、洪珮倫、湯妙行、王心玫、黃至堯、邱福千
	<b>鋁摻雜於二氧化鋯薄膜之反鐵電電容的可靠度分析</b> 劉雨華、林立翔、呂紹豪、盧信沖、王哲麒
	<b>Chairman: 吳添立</b>
10:30 ~ 10:50	<b>Coffee Break</b>
10:50 ~ 11:50	<b>Keynote Speech (II)</b> <b>Automotive Electronics Reliability</b> Allan Tseng Integrated Service Technology
	<b>Chairman: 邱進峯</b>
11:50 ~ 13:00	<b>Lunch</b>
13:00 ~ 14:00	<b>Invited Talk (III)</b> <b>Automotive Transient Voltage Suppressor TVS</b> 李健銘 晶焱科技
	<b>Chairman: 邱進峯</b>
14:00 ~ 14:20	<b>Coffee Break</b>
14:20 ~ 16:50	<b>Session C – ESD/EOS (II)</b>
	<b>圓形超高壓 nLDMOS 同心圓式 Poly 2 與漂移區超接面離散調變對抗 ESD 能力之影響</b> Zhi-Wei Liu, Shen-Li Chen, Zhong-Yi Lai, Xing-Chen Mai, Yu-Jie Chung
	<b>超高壓 nLDMOS 操作電壓調整對 ESD 可靠度能力探討</b> Zhong-Yi Lai, Shen-Li Chen, Po-Lin Lin, Zhi-Wei Liu and Xing-Chen Mai
	<b>Study on Bi-directional ESD Protection Device for High-Voltage FlexRay Applications</b> Yu-Hsin Li, Ming-Dou Ker, Chih-Hsuan Lin, Yeh-Ning Jou, and Jian-Hsing Lee
	<b>全 P 型電晶體之靜電放電防護設計</b> 王俊捷、戴子鈞、林群祐
	<b>Electrostatic Discharge Detector for Manufacturing Field Control</b> I-Hsuan Wu and Ming-Dou Ker
	<b>Chairman: 黃至堯</b>